

November 2013

FQP19N20

N-Channel QFET[®] MOSFET 200 V, 19.4 A, 150 m Ω

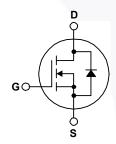
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 19.4 A, 200 V, $R_{DS(on)}$ = 150 m Ω (Max.) @ V_{GS} = 10 V, I_D = 9.7 A
- Low Gate Charge (Typ. 31 nC)
- Low Crss (Typ. 30 pF)
- · 100% Avalanche Tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQP19N20	Unit
V_{DSS}	Drain-Source Voltage		200	V
I _D	Drain Current - Continuous (T _C = 25°C)		19.4	Α
	- Continuous (T _C = 100	°C)	12.3	А
I _{DM}	Drain Current - Pulsed	(Note 1)	78	A
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	250	mJ
I _{AR}	Avalanche Current	(Note 1)	19.4	A
E _{AR}	Repetitive Avalanche Energy	(Note 1)	14	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3		5.5	V/ns
P _D	Power Dissipation (T _C = 25°C)		140	W
	- Derate above 25°C		1.12	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQP19N20	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.89	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQP19N20	FQP19N20	TO-220	Tube	N/A	N/A	50 units

Electrical Characteristics

T_C = 25°C unless otherwise noted.

Parameter	Test Conditions	Min	Тур	Max	Unit
aracteristics					
Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	200			V
Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.18		V/°C
/ ΔT _J Coefficient IDSS Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V			1	μΑ
	V _{DS} = 160 V, T _C = 125°C			10	μΑ
Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
aracteristics					
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 9.7 A		0.12	0.15	Ω
Forward Transconductance	V _{DS} = 40 V, I _D = 9.7 A		14.5		S
nic Characteristics			4000	4000	
	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		-		pF
					pF
Reverse Transfer Capacitance			30	40	pF
ing Characteristics					
Turn-On Delay Time	$V_{DD} = 100 \text{ V}, I_{D} = 19.4 \text{ A},$ $R_{C} = 25 \Omega$		20	50	ns
Turn-On Rise Time			190	390	ns
Turn-Off Delay Time			55	120	ns
Turn-Off Fall Time	(Note 4)	/	80	170	ns
Total Gate Charge	V _{DS} = 160 V, I _D = 19.4 A,		31	40	nC
Gate-Source Charge	V _{GS} = 10 V	/	8.6		nC
Gate-Drain Charge	(Note 4)		13.5		nC
Gale-Dialii Charge					
, and the second	nd Maximum Ratings				
Source Diode Characteristics ar Maximum Continuous Drain-Source Dio				19.4	A
Source Diode Characteristics ar	ode Forward Current			19.4 78	
	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse aracteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance ic Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge			aracteristics Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ 200 Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced to 25°C 0.18 Zero Gate Voltage Drain Current $V_{DS} = 200 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{DS} = 100 \text{ V}$, $V_{DS} = 9.7 \text{ A}$ 3.0 Gate-Body Leakage Current, Reverse $V_{DS} = 100 \text{ V}$, $V_{DS} = 100 \text{ V}$,	aracteristics Drain-Source Breakdown Voltage V _{GS} = 0 V, I _D = 250 μA 200 Breakdown Voltage Temperature Coefficient I _D = 250 μA, Referenced to 25°C 0.18 Zero Gate Voltage Drain Current V _{DS} = 200 V, V _{GS} = 0 V 1 Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse V _{GS} = 160 V, T _C = 125°C 100 Gate-Body Leakage Current, Reverse V _{GS} = 30 V, V _{DS} = 0 V 100 Gate-Body Leakage Current, Reverse V _{GS} = -30 V, V _{DS} = 0 V 100 Gate-Body Leakage Current, Reverse V _{GS} = -30 V, V _{DS} = 0 V 100 Gate-Body Leakage Current, Reverse V _{GS} = -30 V, V _{DS} = 0 V 100 Gate-Body Leakage Current, Reverse V _{DS} = V _{GS} , I _D = 250 μA 3.0 010 0.10 0.12 0.15 0.12

Q_{rr}

 t_{rr}

Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature. 2. L = 1.0 mH, I_{AS} = 19.4 A, V_{DD} = 50 V, R_G = 25 Ω , starting T_J = 25°C. 3. I_{SD} \leq 19.4 A, di/dt \leq 300 A/µs, V_{DD} \leq BV_{DSS}, starting T_J = 25°C. 4. Essentially independent of operating temperature.

Reverse Recovery Time

Reverse Recovery Charge

140

0.69

ns

μС

V_{GS} = 0 V, I_S = 19.4 A,

 $dI_F / dt = 100 A/\mu s$

Typical Characteristics

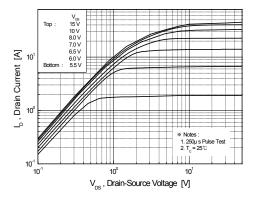


Figure 1. On-Region Characteristics

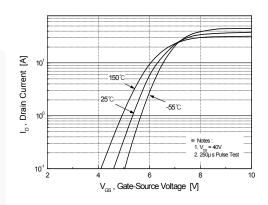


Figure 2. Transfer Characteristics

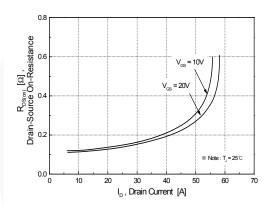


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

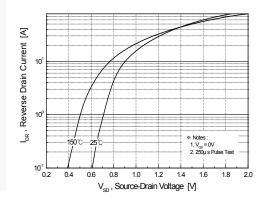


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

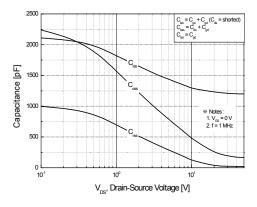


Figure 5. Capacitance Characteristics

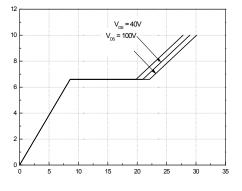
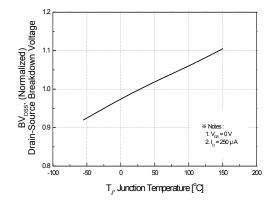


Figure 6. Gate Charge Characteristics

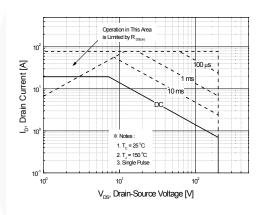
Typical Characteristics (continued)



30
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(parity

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



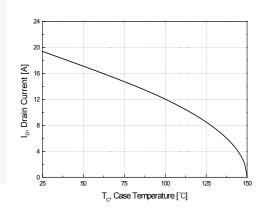


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

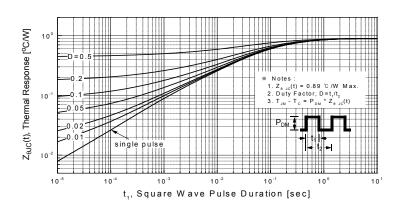


Figure 11. Transient Thermal Response Curve

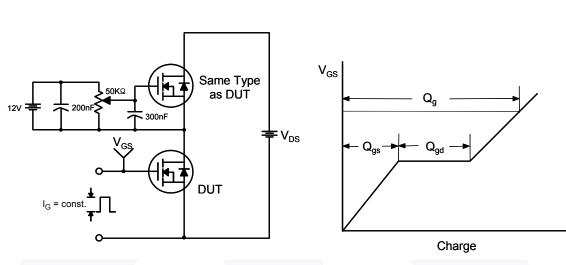


Figure 12. Gate Charge Test Circuit & Waveform

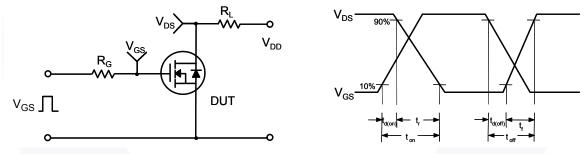


Figure 13. Resistive Switching Test Circuit & Waveforms

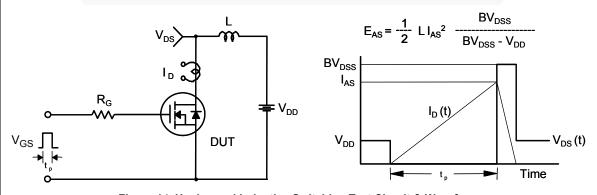
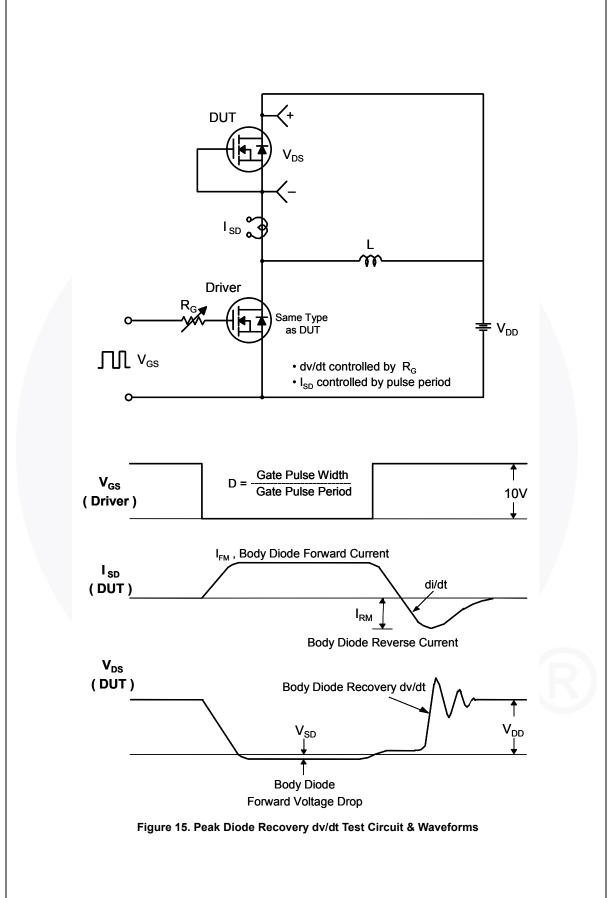
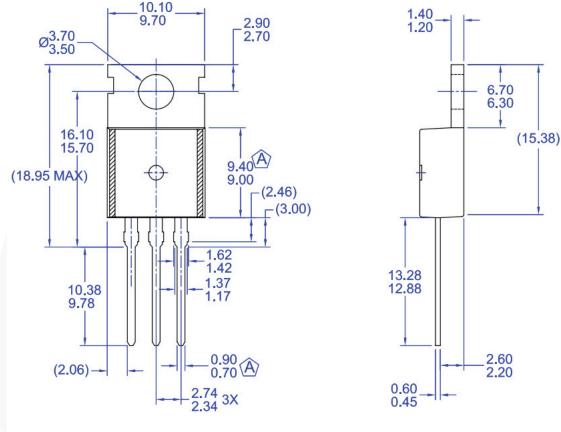
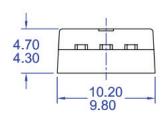


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



Mechanical Dimensions





NOTES:

- (A) CONFORMS TO JEDEC TO-220 VARIATION AB EXCEPT WHERE NOTED
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D) DRAWING FILE/REVISION: MKT-TO220Y03REV1

Figure 16. TO220, Molded, 3-Lead, Jedec Variation AB

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